

Modelling polycrystalline microstructures by tessellations

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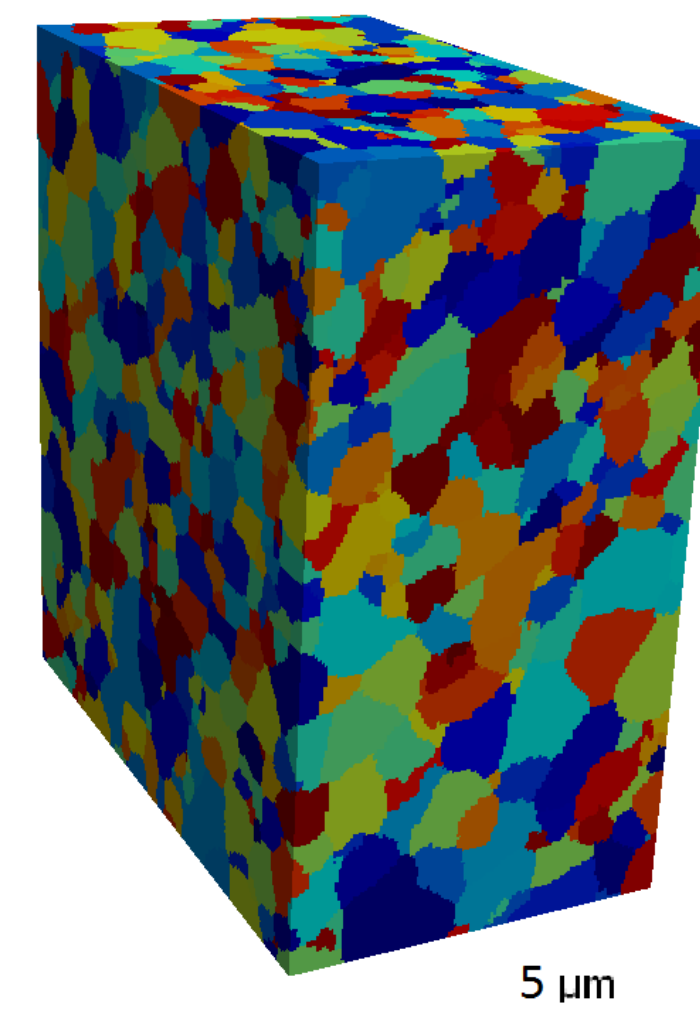
Description of the problem

Representation of the 3D microstructures by parametric tessellation models allows an efficient **conversion of voxel-based data to vector-based data**.

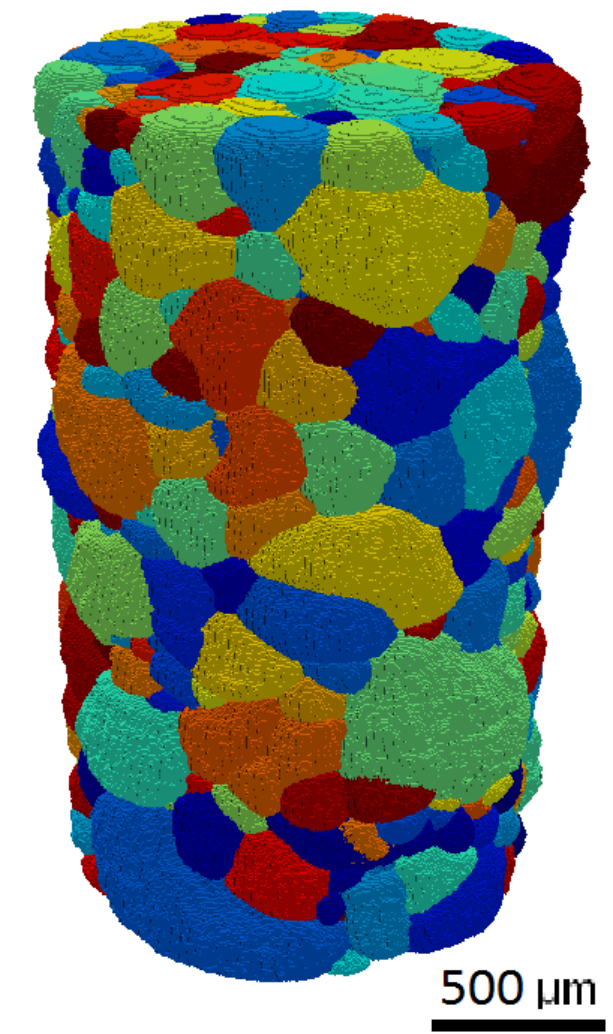
Advantages

- significant **data reduction**
- **avoids processing steps** related to smoothing of grain boundaries
- **consistent estimation** of size and shape characteristics
- allows for generation of **virtual microstructures**

Sample I



Sample II



Visualization of grains in the 3D microstructure of Al-3wt.%Mg-0.2wt.%Sc (Sample I) and Al-1wt.%Mg (Sample II).

Model fitting

For fitting a tessellation to empirical image data I , we use a stochastic optimization method known as **simulated annealing**.

Algorithm

- 1) Initialization.** Identify initial parameters $\{x_i, M_i, r_i\}$. Set $n = 1$.
- 2) Modification.** Modify a single parameter of a random cell.
- 3) Updating.** Evaluate the current discrepancy $D^{(n)}(I, P)$, counting incorrectly assigned voxels, and the new discrepancy $D^{(new)}(I, P)$. Accept the new state (i.e. set $D^{(n+1)}(I, P) = D^{(new)}(I, P)$) with probability

$$\alpha = \begin{cases} 1 & \text{if } D^{(new)}(I, P) \leq D^{(n)}(I, P) \\ \exp\left\{-\frac{D^{(n)}(I, P) - D^{(new)}(I, P)}{T}\right\} & \text{otherwise} \end{cases}$$

- 4) Iteration.** If a predefined stopping condition is met, stop. Otherwise set $n = n + 1$ and repeat from step 2.

➤ A **tessellation** is a division of \mathbb{R}^k into a countable collection of non-overlapping sets called *cells* or *grains*.

➤ We use **parametric tessellation models** generated by a marked point pattern $P = \{(x_i, \theta_i) : x_i \in \mathbb{R}^k, \theta_i \in \Theta\}$, where Θ is a parametric space.

➤ The **cells** of a tessellation P are defined by

$$C_i = \{x \in \mathbb{R}^k : d(x, (x_i, \theta_i)) \leq d(x, (x_j, \theta_j)), \forall j \neq i\}$$

with certain distance measure d .

➤ We focus on **generalized balanced power diagrams**

(GBPD) defined by $d(x, (x_i, M_i, r_i)) = (x - x_i)^T M_i (x - x_i) - r_i$, $r_i \in \mathbb{R}, M_i \in \mathbb{R}^{3 \times 3}$ a symmetric positive definite matrix

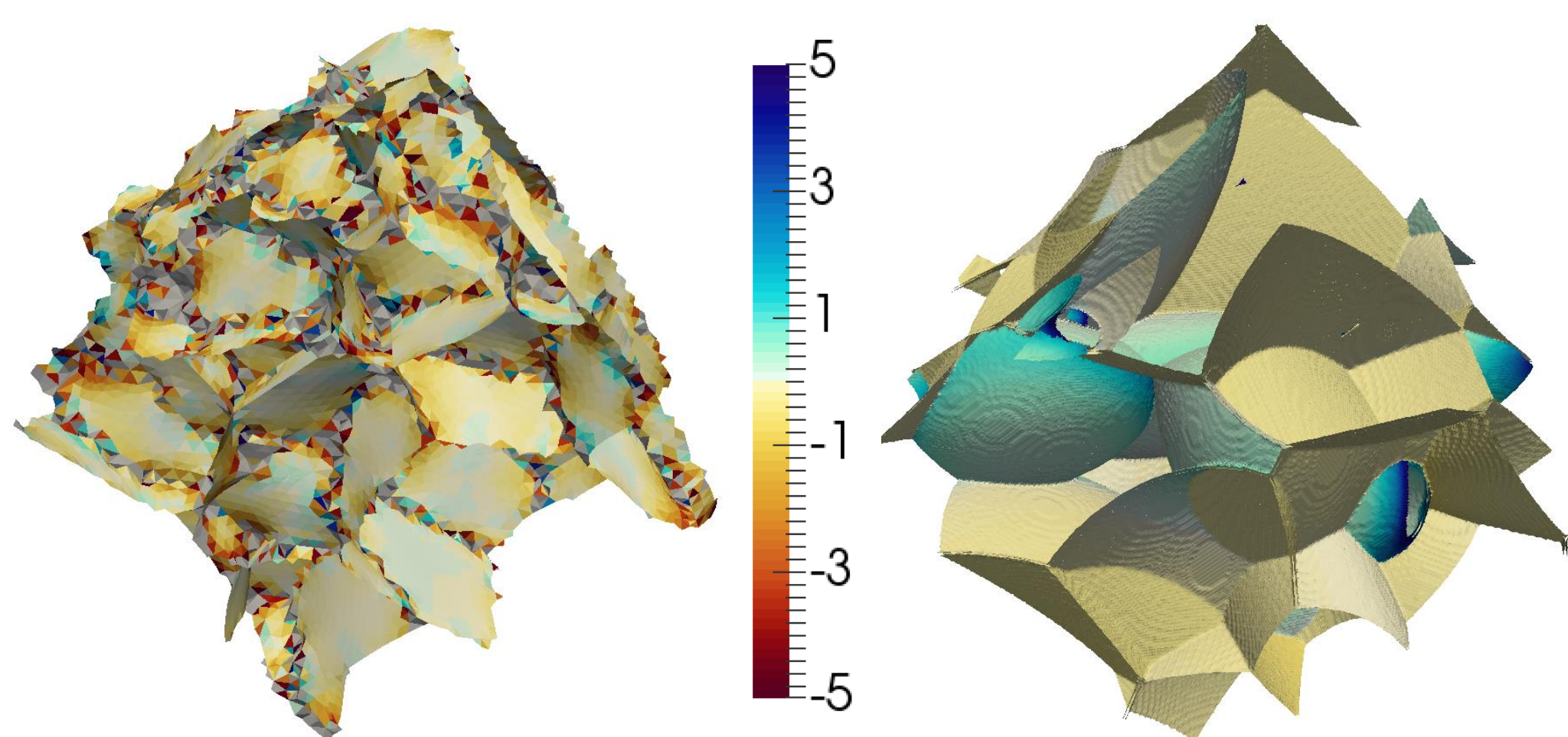
Results (comparison of GBPD with some other common models)

		Sample I	Sample II
Voronoi tessellation	$d(x, x_i) = \ x - x_i\ $	57.5	58.6
Laguerre tessellation	$d(x, (x_i, r_i)) = \ x - x_i\ ^2 - r_i$	79.4	85.4
spherical grain growth model	$d(x, (x_i, r_i)) = \ x - x_i\ /r_i$	83.1	86.6
GBPD	$d(x, (x_i, M_i, r_i)) = (x - x_i)^T M_i (x - x_i) - r_i$	92.0	95.0

percentage of correctly assigned voxels

Estimation of geometric characteristics

Grain boundaries in the GBPD model are parts of **quadric surfaces**. Thus, **size and shape characteristics** can be computed from analytical formulas.



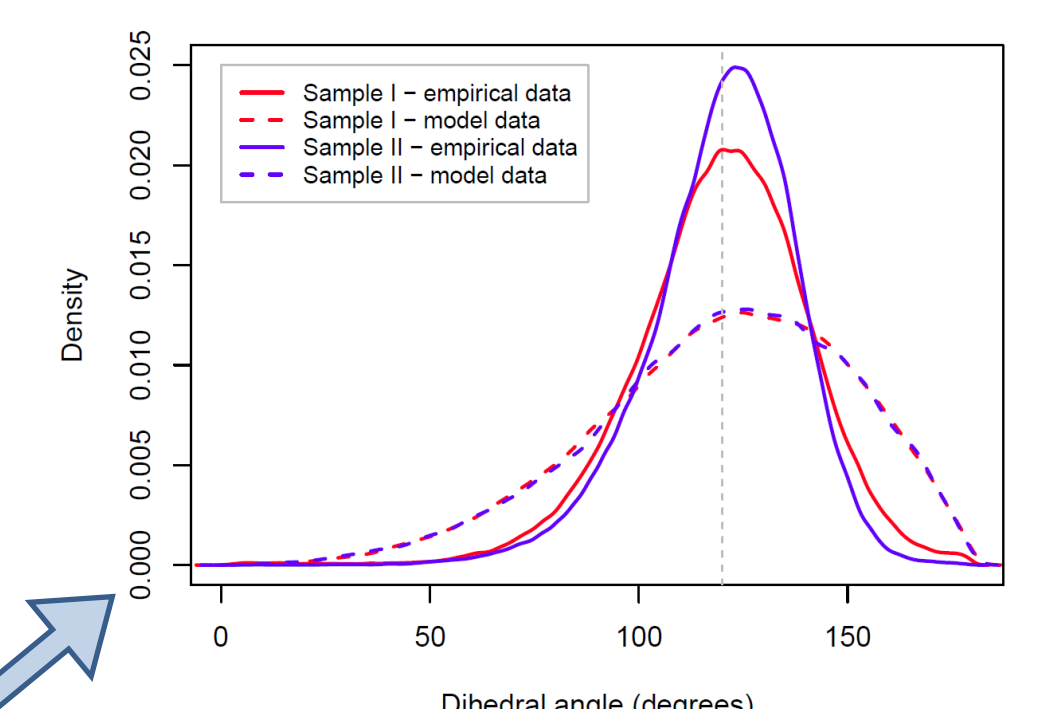
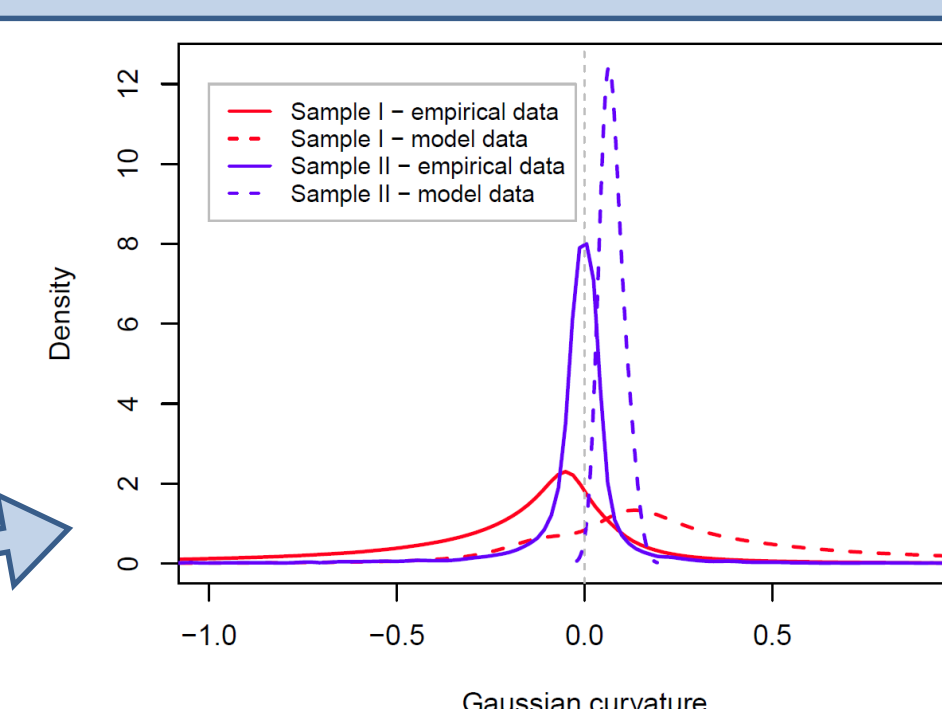
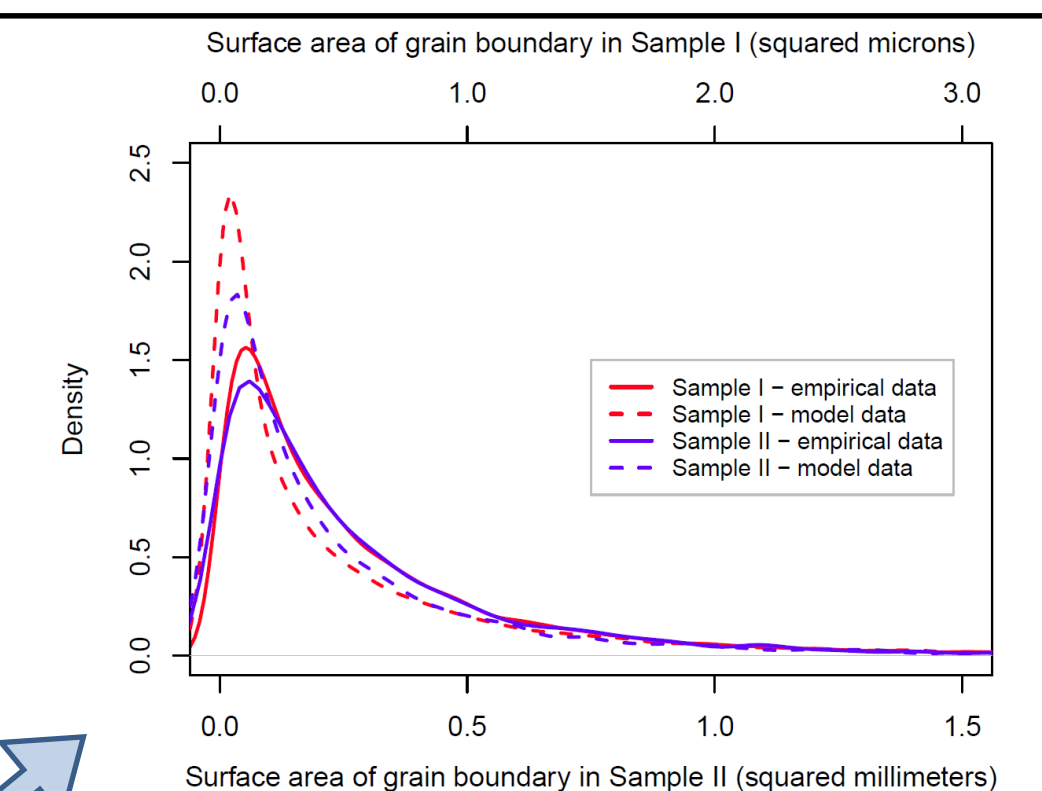
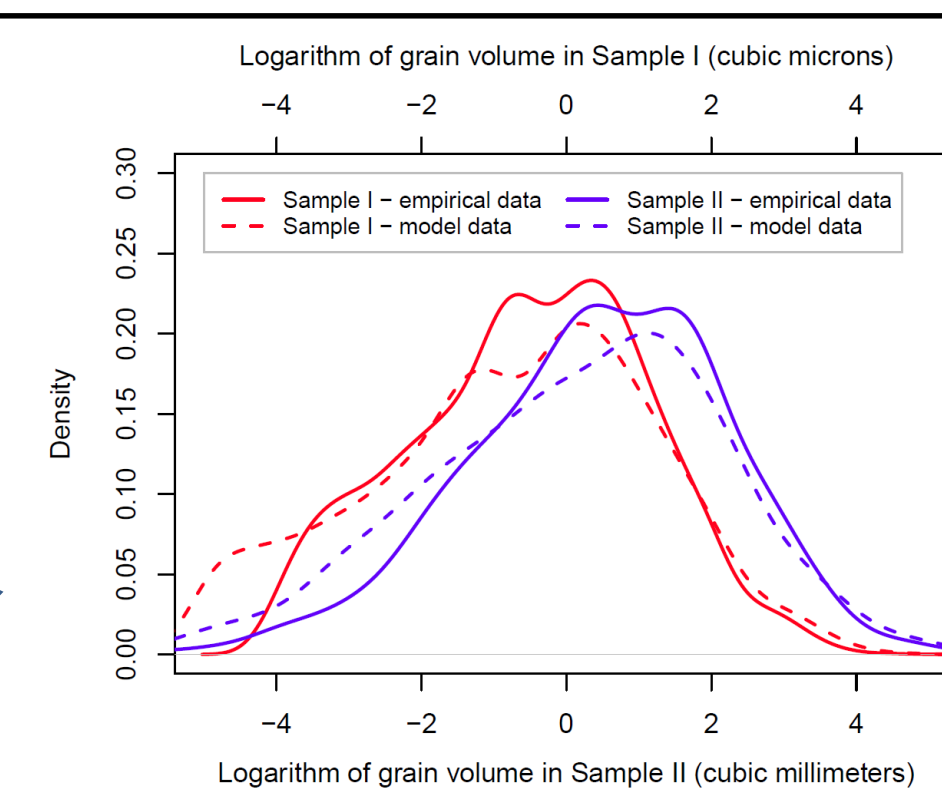
Cutout of grain boundary network fitted by triangular surface mesh (left) and the GBPD model (right), coloured with respect to Gaussian curvature.

Size characteristics

- 1) Volume** of grains
- 2) Surface area** of grain boundaries
- 3) Length** of triple junctions

Local shape characteristics

- 1) Curvature** at grain boundaries
- 2) Dihedral angle** at triple junctions



References

- [1] O. Šedivý, T. Brereton, D. Westhoff, L. Polívka, V. Beneš, V. Schmidt and A. Jäger. 3D reconstruction of grains in polycrystalline materials using a tessellation model with curved grain boundaries. *Philosophical Magazine* 96:18 (2016), 1926-49.
- [2] O. Šedivý, J.M. Dake, C.E. Krill III, V. Schmidt and A. Jäger. Description of the 3D morphology of grain boundaries in aluminum alloys using tessellation models generated by ellipsoids. *Image Analysis & Stereology* 36 (2017), 5-13.